

IRF9Z24LPBF-VB Datasheet

P-Channel 60-V (D-S) MOSFET

PRODUCT SUMMARY					
V _{DS} (V)	$R_{DS(on)}(\Omega)$	I _D (A) ^a	Q _g (Typ.)		
- 60	0.0160at V _{GS} = - 10 V	- 53	76 nC		
- 60	0.0200 at $V_{GS} = -4.5 \text{ V}$	- 42	70110		

FEATURES

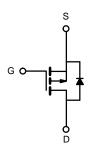
- Trench Power MOSFET
- 100 % UIS Tested

APPLICATIONS

Load Switch







P-Channel	MOSFET
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ABSOLUTE MAXIMUM RATINGS	(T _A = 25 °C, unle	ess otherwise n	oted)	
Parameter	Symbol	Limit	Unit	
Drain-Source Voltage	Drain-Source Voltage			V
Gate-Source Voltage		V _{GS}	± 20]
	T _C = 25 °C		- 53 ^a	
Continuous Drain Current (T _{.I} = 150 °C)	T _C = 70 °C		- 46.8	
Continuous Diain Current (1 j = 130 °C)	T _A = 25 °C	I _D	9.2 ^b	A
	T _A = 70 °C		- 8.1 ^b	
Pulsed Drain Current	•	I _{DM}	- 150	
Avalanche Current Pulse	L = 0.1 mH	I _{AS}	- 45	
Single Pulse Avalanche Energy	L = 0.1 IIII	E _{AS}	101	mJ
Continuous Source-Drain Diode Current	T _C = 25 °C	I-	69 ^a	A
Continuous Source-Diam blode Current	T _A = 25 °C	I _S	2.1 ^b	
	T _C = 25 °C		104.2 ^a	
Maximum Dawar Dissination	T _C = 70 °C		66.7 ^a	w
Maximum Power Dissipation	T _A = 25 °C	P _D	3.1 ^b	
	T _A = 70 °C		2 ^b	
Operating Junction and Storage Temperature Ra	T _J , T _{stg}	- 55 to 150	°C	

THERMAL RESISTANCE RATINGS						
Parameter		Symbol	Typical	Maximum	Unit	
Maximum Junction-to-Ambient ^b	Steady State	R _{thJA}	33	40	°C/W	
Maximum Junction-to-Case	Steady State	R _{thJC}	0.98	1.2	3C/VV	

Notes:

- a. Based on T_C = 25 °C.
- b. Surface mounted on 1" x 1" FR4 board.



Parameter	Symbol	Test Conditions	Min.	Тур.	Max.	Unit
Static						
Drain-Source Breakdown Voltage	V_{DS}	$V_{GS} = 0 \text{ V}, I_D = -250 \mu\text{A}$	- 60			V
V _{DS} Temperature Coefficient	$\Delta V_{DS}/T_{J}$	I _D = - 250 μA		68		mV/°C
V _{GS(th)} Temperature Coefficient	$\Delta V_{GS(th)}/T_{J}$	i _D = - 250 μA		- 5.2		IIIV/C
Gate-Source Threshold Voltage	V _{GS(th)}	$V_{DS} = V_{GS}, I_{D} = -250 \mu A$	- 1		- 3	V
Gate-Source Leakage	I _{GSS}	$V_{DS} = 0 \text{ V}, V_{GS} = \pm 20 \text{ V}$			± 100	nA
Zana Cata Valta na Duain Commant	1	V _{DS} = - 60 V, V _{GS} = 0 V			- 1	μΑ
Zero Gate Voltage Drain Current	I _{DSS}	V _{DS} = - 60 V, V _{GS} = 0 V, T _J = 55 °C			- 10	
On-State Drain Current ^a	I _{D(on)}	V _{DS} = - 5 V, V _{GS} = - 10 V	- 120			Α
D : 0	В	V _{GS} = - 10 V, I _D = - 30 A		0.0160		
Drain-Source On-State Resistance ^a	R _{DS(on)}	V _{GS} = - 4.5 V, I _D = - 20 A		0.0200		Ω
Forward Transconductance ^a	9 _{fs}	V _{DS} = - 15 V, I _D = - 50 A	20			S
Dynamic ^b	•					•
Input Capacitance	C _{iss}			3500		pF
Output Capacitance	C _{oss}	$V_{DS} = -25 \text{ V}, V_{GS} = 0 \text{ V}, f = 1 \text{ MHz}$		390		
Reverse Transfer Capacitance	C _{rss}			290		
Total Cata Charge	Q _g	V _{DS} = - 30 V, V _{GS} = - 10 V, I _D = - 55 A		76	115	nC
Total Gate Charge				38	60	
Gate-Source Charge	Q_{gs}	$V_{DS} = -30 \text{ V}, V_{GS} = -4.5 \text{ V}, I_{D} = -55 \text{ A}$		16		
Gate-Drain Charge	Q_{gd}			19		
Gate Resistance	R _g	f = 1 MHz		5.2		Ω
Turn-On Delay Time	t _{d(on)}			10	15	
Rise Time	t _r	V_{DD} = - 2 V, R_L = 2 Ω		7	15	ns
Turn-Off Delay Time	t _{d(off)}	$I_D \cong$ - 10 A, V_{GEN} = - 10 V, R_g = 1 Ω		70	110	
Fall Time	t _f			40	60	
Drain-Source Body Diode Characteristic	s					_
Continuous Source-Drain Diode Current	I _S	T _C = 25 °C			- 69	_
Pulse Diode Forward Current ^a	I _{SM}				- 150	A
Body Diode Voltage	V_{SD}	I _S = - 30 A		- 1	- 1.5	V
Body Diode Reverse Recovery Time	t _{rr}			45	68	ns
Body Diode Reverse Recovery Charge	Q _{rr}			59	120	nC
Reverse Recovery Fall Time	t _a	$I_F = -50 \text{ A}, \text{ di/dt} = 100 \text{ A/}\mu\text{s}, T_J = 25 \text{ °C}$		29		
Reverse Recovery Rise Time	t _b			16		ns

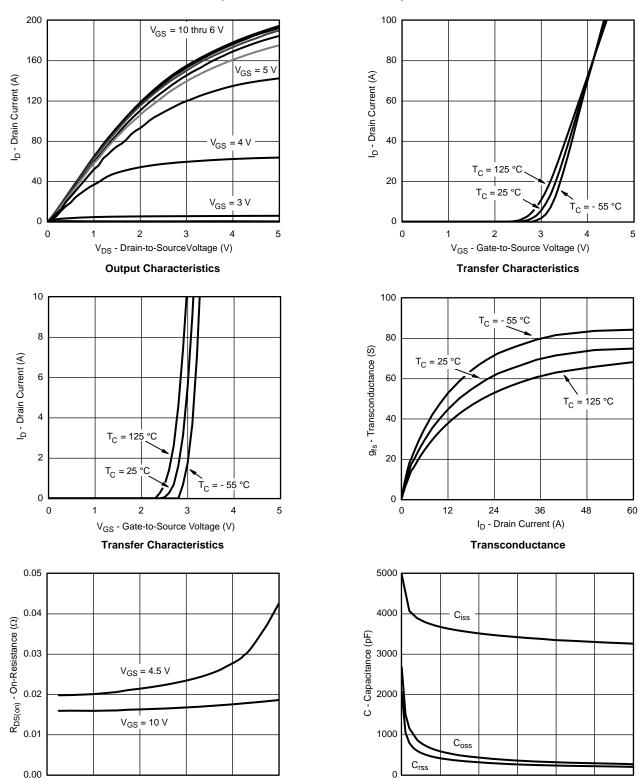
Notes:

- a. Pulse test; pulse width $\leq 300~\mu s,$ duty cycle $\leq 2~\%.$
- b. Guaranteed by design, not subject to production testing.

Stresses beyond those listed under "Absolute Maximum Ratings" may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated in the operational sections of the specifications is not implied. Exposure to absolute maximum rating conditions for extended periods may affect device reliability.



TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



服务热线:400-655-8788

I_D - Drain Current (A)

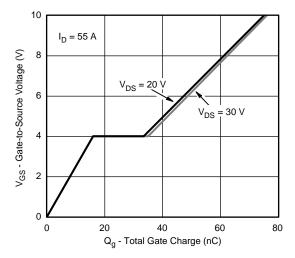
On-Resistance vs. Drain Current

Capacitance

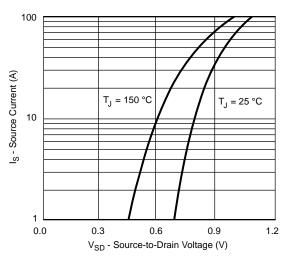
V_{DS} - Drain-to-Source Voltage (V)



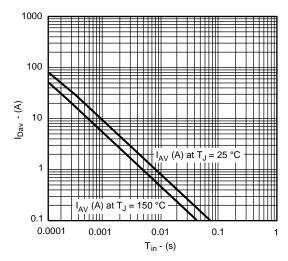
TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)



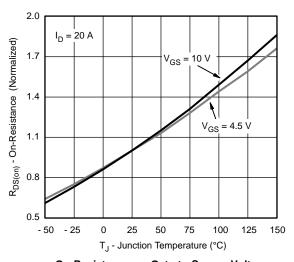




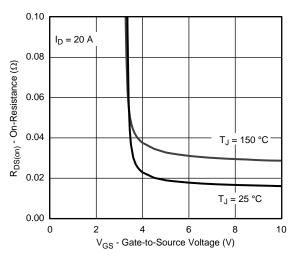
Source-Drain Diode Forward Voltage



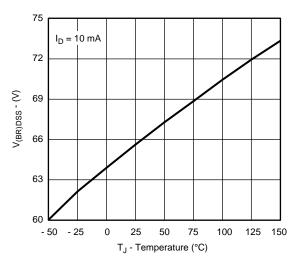
Single Pulse Avalanche Current Capability vs. Time



On-Resistance vs. Gate-to-Source Voltage



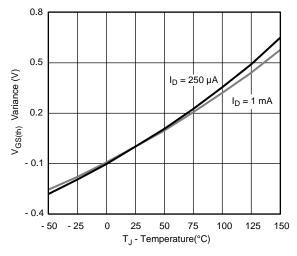
On-Resistance vs. Gate-to-Source Voltage

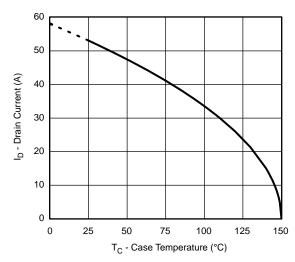


Drain-Source Breakdown Voltage vs. Junction Temperature

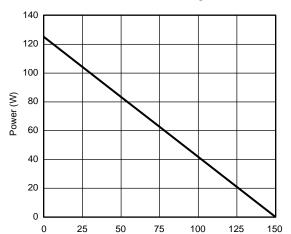


TYPICAL CHARACTERISTICS (25 °C, unless otherwise noted)

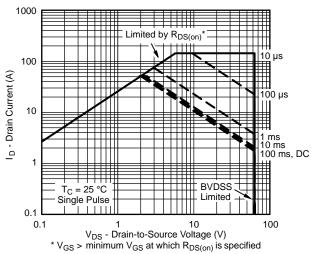




Threshold Voltage

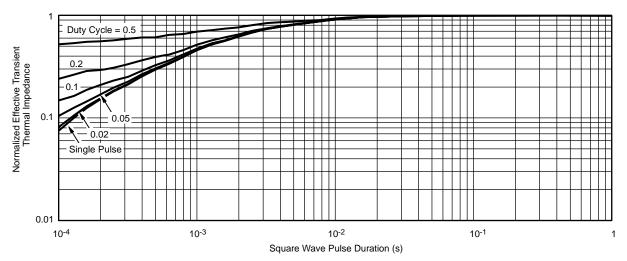


Max. Drain Current vs. Case Temperature



$\label{eq:TJ-Temperature CC} \textbf{Power Derating, Junction-to-Case}$

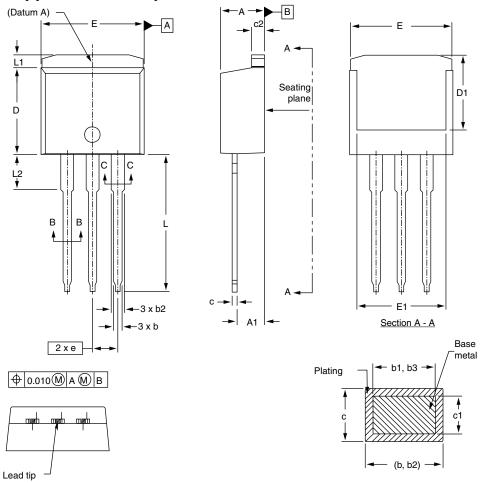




Normalized Thermal Transient Impedance, Junction-to-Case



I²PAK (TO-262) (HIGH VOLTAGE)



	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
Α	4.06	4.83	0.160	0.190
A1	2.03	3.02	0.080	0.119
b	0.51	0.99	0.020	0.039
b1	0.51	0.89	0.020	0.035
b2	1.14	1.78	0.045	0.070
b3	1.14	1.73	0.045	0.068
С	0.38	0.74	0.015	0.029
c1	0.38	0.58	0.015	0.023
c2	1.14	1.65	0.045	0.065

	MILLIMETERS		INC	HES
DIM.	MIN.	MAX.	MIN.	MAX.
D	8.38	9.65	0.330	0.380
D1	6.86	-	0.270	-
E	9.65	10.67	0.380	0.420
E1	6.22	-	0.245	-
е	2.54 BSC		0.100 BSC	
L	13.46	14.10	0.530	0.555
L1	-	1.65	-	0.065
L2	3.56	3.71	0.140	0.146

Section B - B and C - C Scale: None

ECN: S-82442-Rev. A, 27-Oct-08

DWG: 5977

Notes

- 1. Dimensioning and tolerancing per ASME Y14.5M-1994.
- 2. Dimension D and E do not include mold flash. Mold flash shall not exceed 0.127 mm per side. These dimensions are measured at the outmost extremes of the plastic body.
- 3. Thermal pad contour optional within dimension E, L1, D1, and E1.
- 4. Dimension b1 and c1 apply to base metal only.



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